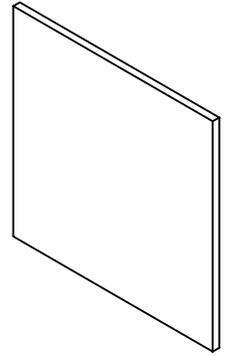
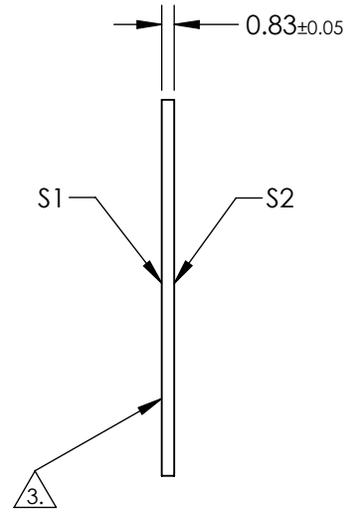
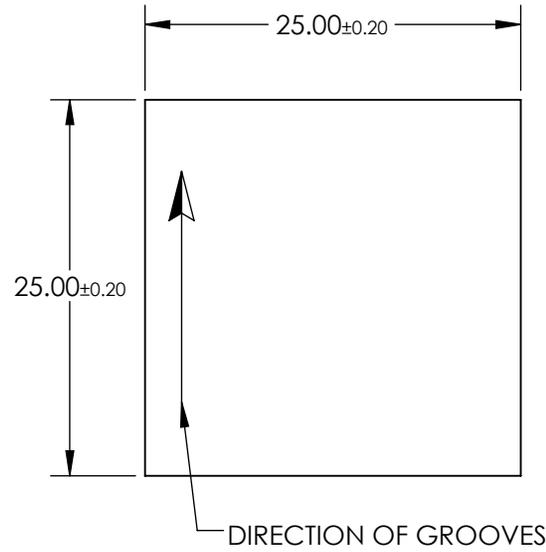
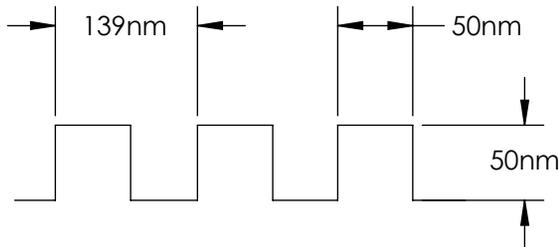


NOTES:

1. SUBSTRATE MATERIAL:
Single Crystal Silicon
2. PERIOD: 139 ±6.95nm
LINE WIDTH: 50 ±5nm
GROOVE DEPTH: 50 ±7.5nm
3.  RIE TREATED SURFACE
4. RoHS COMPLIANT



CROSS SECTION VIEW OF GRATING SURFACE



**FOR INFORMATION ONLY:
DO NOT MANUFACTURE
PARTS TO THIS DRAWING**

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	60-40 (within CA)	FINE GRIND
CLEAR APERTURE	24.00 x 24.00	N/A
BEVEL	PROTECTED AS NEEDED	PROTECTED AS NEEDED



ALL DIMS IN mm

 **Edmund Optics®**

TITLE

II-VI LightSmyth™ 139nm, 50nm Groove
Depth, 25mm Sq. Linear Silicon Nanostamp

DWG NO

16858

SHEET
1 OF 1